

Abstract

5 **SOCKET OR ADAPTER DEVICE FOR SEMICONDUCTOR DEVICES,
METHOD FOR TESTING SEMICONDUCTOR DEVICES, AND SYSTEM COM-
PRISING AT LEAST ONE SOCKET OR ADAPTER DEVICE**

10 The invention relates to a method for testing semiconduc-
tor devices, to a system including at least one socket or
adapter device, and to a socket or adapter device, in
particular for semiconductor devices, having at least one
connection pin which is designed such that it is adapted
to be introduced into a corresponding contact device of a
device to which the socket or adapter device is to be
connected, wherein the connection pin is designed such
15 that a clamping connection is provided between the con-
tact device and the connection pin when the connection
pin is introduced into the contact device.

20

- Figure 4 -

25